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Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1206
Number of Logic Elements/Cells	12060
Total RAM Bits	239616
Number of I/O	185
Number of Gates	-
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	256-BGA
Supplier Device Package	256-FBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep1c12f256i7

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Table 1–1. Cyclone Device Features (Part 2 of 2)										
Feature	EP1C3	EP1C4	EP1C6	EP1C12	EP1C20					
Total RAM bits	59,904	78,336	92,160	239,616	294,912					
PLLs	1	2	2	2	2					
Maximum user I/O pins (1)	104	301	185	249	301					

Note to Table 1–1:

(1) This parameter includes global clock pins.

Cyclone devices are available in quad flat pack (QFP) and space-saving FineLine[®] BGA packages (see Tables 1–2 through 1–3).

Table 1-2. (Table 1–2. Cyclone Package Options and I/O Pin Counts										
Device	100-Pin TQFP (1)	144-Pin TQFP (1), (2)	240-Pin PQFP (1)	256-Pin FineLine BGA	324-Pin FineLine BGA	400-Pin FineLine BGA					
EP1C3	65	104	_	_	_	_					
EP1C4	_	_	_	_	249	301					
EP1C6	_	98	185	185	_	_					
EP1C12	_	_	173	185	249	_					
EP1C20	_	_	_	_	233	301					

Notes to Table 1–2:

- (1) TQFP: thin quad flat pack. PQFP: plastic quad flat pack.
- (2) Cyclone devices support vertical migration within the same package (i.e., designers can migrate between the EP1C3 device in the 144-pin TQFP package and the EP1C6 device in the same package).

Vertical migration means you can migrate a design from one device to another that has the same dedicated pins, JTAG pins, and power pins, and are subsets or supersets for a given package across device densities. The largest density in any package has the highest number of power pins; you must use the layout for the largest planned density in a package to provide the necessary power pins for migration.

For I/O pin migration across densities, cross-reference the available I/O pins using the device pin-outs for all planned densities of a given package type to identify which I/O pins can be migrated. The Quartus® II software can automatically cross-reference and place all pins for you when given a device migration list. If one device has power or ground pins, but these same pins are user I/O on a different device that is in the migration path,the Quartus II software ensures the pins are not used as user I/O in the Quartus II software. Ensure that these pins are connected

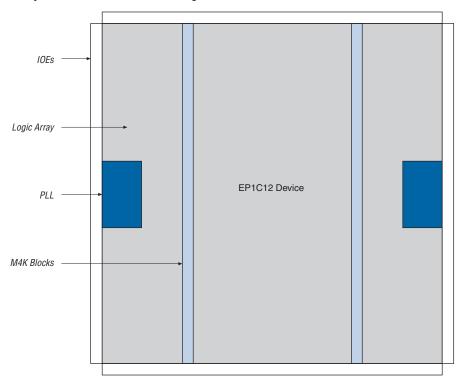


Figure 2-1. Cyclone EP1C12 Device Block Diagram

The number of M4K RAM blocks, PLLs, rows, and columns vary per device. Table 2–1 lists the resources available in each Cyclone device.

Table 2–1. Cyclone Device Resources										
Device	M4K	RAM	PLLs	LAB Columns	LAB Rows					
Device	Columns	Blocks	PLLS	LAD CUIUIIIIS						
EP1C3	1	13	1	24	13					
EP1C4	1	17	2	26	17					
EP1C6	1	20	2	32	20					
EP1C12	2	52	2	48	26					
EP1C20	2	64	2	64	32					

Logic Array Blocks

Each LAB consists of 10 LEs, LE carry chains, LAB control signals, a local interconnect, look-up table (LUT) chain, and register chain connection lines. The local interconnect transfers signals between LEs in the same LAB. LUT chain connections transfer the output of one LE's LUT to the adjacent LE for fast sequential LUT connections within the same LAB. Register chain connections transfer the output of one LE's register to the adjacent LE's register within a LAB. The Quartus® II Compiler places associated logic within a LAB or adjacent LABs, allowing the use of local, LUT chain, and register chain connections for performance and area efficiency. Figure 2–2 details the Cyclone LAB.

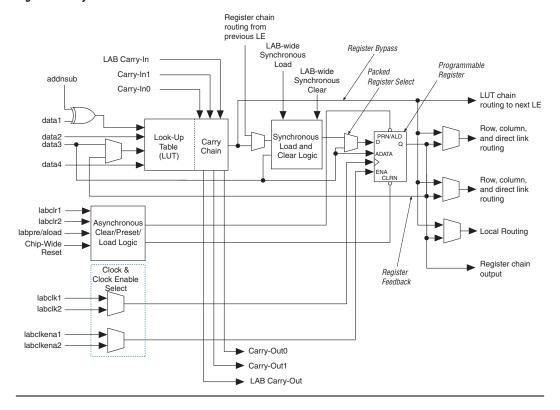
Row Interconnect Column Interconnect Direct link interconnect from Direct link adjacent block interconnect from adjacent block Direct link Direct link interconnect to interconnect to adjacent block adjacent block LÄB Local Interconnect

Figure 2-2. Cyclone LAB Structure

LAB Interconnects

The LAB local interconnect can drive LEs within the same LAB. The LAB local interconnect is driven by column and row interconnects and LE outputs within the same LAB. Neighboring LABs, PLLs, and M4K RAM blocks from the left and right can also drive a LAB's local interconnect through the direct link connection. The direct link connection feature minimizes the use of row and column interconnects, providing higher

Figure 2-5. Cyclone LE



Each LE's programmable register can be configured for D, T, JK, or SR operation. Each register has data, true asynchronous load data, clock, clock enable, clear, and asynchronous load/preset inputs. Global signals, general-purpose I/O pins, or any internal logic can drive the register's clock and clear control signals. Either general-purpose I/O pins or internal logic can drive the clock enable, preset, asynchronous load, and asynchronous data. The asynchronous load data input comes from the data3 input of the LE. For combinatorial functions, the LUT output bypasses the register and drives directly to the LE outputs.

Each LE has three outputs that drive the local, row, and column routing resources. The LUT or register output can drive these three outputs independently. Two LE outputs drive column or row and direct link routing connections and one drives local interconnect resources. This allows the LUT to drive one output while the register drives another output. This feature, called register packing, improves device utilization because the device can use the register and the LUT for unrelated

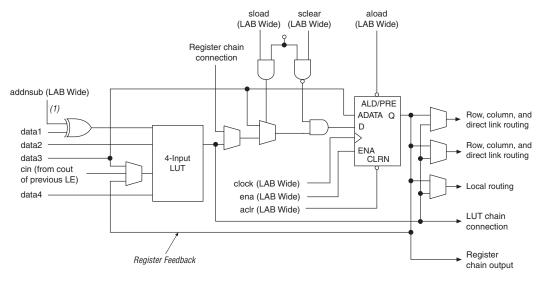
preset/load, synchronous clear, synchronous load, and clock enable control for the register. These LAB-wide signals are available in all LE modes. The addnsub control signal is allowed in arithmetic mode.

The Quartus II software, in conjunction with parameterized functions such as library of parameterized modules (LPM) functions, automatically chooses the appropriate mode for common functions such as counters, adders, subtractors, and arithmetic functions. If required, you can also create special-purpose functions that specify which LE operating mode to use for optimal performance.

Normal Mode

The normal mode is suitable for general logic applications and combinatorial functions. In normal mode, four data inputs from the LAB local interconnect are inputs to a four-input LUT (see Figure 2–6). The Quartus II Compiler automatically selects the carry-in or the data3 signal as one of the inputs to the LUT. Each LE can use LUT chain connections to drive its combinatorial output directly to the next LE in the LAB. Asynchronous load data for the register comes from the data3 input of the LE. LEs in normal mode support packed registers.

Figure 2-6. LE in Normal Mode



Note to Figure 2–6:

This signal is only allowed in normal mode if the LE is at the end of an adder/subtractor chain.

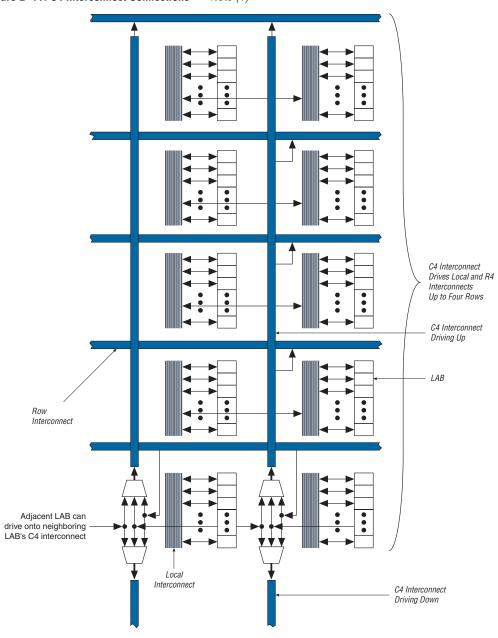


Figure 2–11. C4 Interconnect Connections Note (1)

Note to Figure 2–11:

(1) Each C4 interconnect can drive either up or down four rows.

signal. The output registers can be bypassed. Pseudo-asynchronous reading is possible in the simple dual-port mode of M4K blocks by clocking the read enable and read address registers on the negative clock edge and bypassing the output registers.

When configured as RAM or ROM, you can use an initialization file to pre-load the memory contents.

Two single-port memory blocks can be implemented in a single M4K block as long as each of the two independent block sizes is equal to or less than half of the M4K block size.

The Quartus II software automatically implements larger memory by combining multiple M4K memory blocks. For example, two 256×16-bit RAM blocks can be combined to form a 256×32-bit RAM block. Memory performance does not degrade for memory blocks using the maximum number of words allowed. Logical memory blocks using less than the maximum number of words use physical blocks in parallel, eliminating any external control logic that would increase delays. To create a larger high-speed memory block, the Quartus II software automatically combines memory blocks with LE control logic.

Parity Bit Support

The M4K blocks support a parity bit for each byte. The parity bit, along with internal LE logic, can implement parity checking for error detection to ensure data integrity. You can also use parity-size data words to store user-specified control bits. Byte enables are also available for data input masking during write operations.

Shift Register Support

You can configure M4K memory blocks to implement shift registers for DSP applications such as pseudo-random number generators, multi-channel filtering, auto-correlation, and cross-correlation functions. These and other DSP applications require local data storage, traditionally implemented with standard flip-flops, which can quickly consume many logic cells and routing resources for large shift registers. A more efficient alternative is to use embedded memory as a shift register block, which saves logic cell and routing resources and provides a more efficient implementation with the dedicated circuitry.

The size of a $w \times m \times n$ shift register is determined by the input data width (w), the length of the taps (m), and the number of taps (n). The size of a $w \times m \times n$ shift register must be less than or equal to the maximum number of memory bits in the M4K block (4,608 bits). The total number of shift

Read/Write Clock Mode

The M4K memory blocks implement read/write clock mode for simple dual-port memory. You can use up to two clocks in this mode. The write clock controls the block's data inputs, wraddress, and wren. The read clock controls the data output, rdaddress, and rden. The memory blocks support independent clock enables for each clock and asynchronous clear signals for the read- and write-side registers. Figure 2–20 shows a memory block in read/write clock mode.

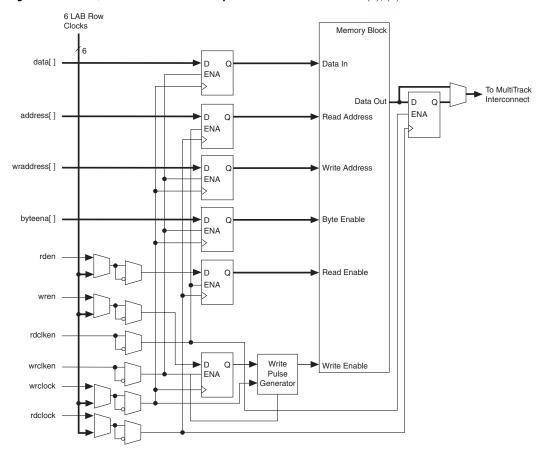


Figure 2–20. Read/Write Clock Mode in Simple Dual-Port Mode Notes (1), (2)

Notes to Figure 2–20:

- (1) All registers shown except the rden register have asynchronous clear ports.
- (2) Violating the setup or hold time on the address registers could corrupt the memory contents. This applies to both read and write operations.

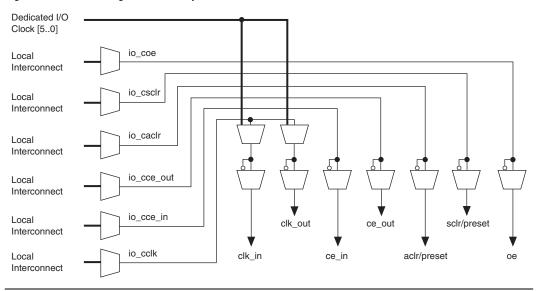
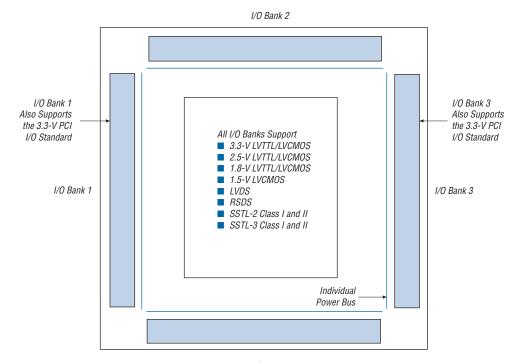


Figure 2-31. Control Signal Selection per IOE

In normal bidirectional operation, you can use the input register for input data requiring fast setup times. The input register can have its own clock input and clock enable separate from the OE and output registers. The output register can be used for data requiring fast clock-to-output performance. The OE register is available for fast clock-to-output enable timing. The OE and output register share the same clock source and the same clock enable source from the local interconnect in the associated LAB, dedicated I/O clocks, or the column and row interconnects. Figure 2–32 shows the IOE in bidirectional configuration.

and DM pins to support a DDR SDRAM or FCRAM interface. I/O bank 1 can also support a DDR SDRAM or FCRAM interface, however, the configuration input pins in I/O bank 1 must operate at 2.5 V. I/O bank 3 can also support a DDR SDRAM or FCRAM interface, however, all the JTAG pins in I/O bank 3 must operate at 2.5 V.

Figure 2–35. Cyclone I/O Banks Notes (1), (2)



I/O Bank 4

Notes to Figure 2–35:

- (1) Figure 2–35 is a top view of the silicon die.
- (2) Figure 2–35 is a graphic representation only. Refer to the pin list and the Quartus II software for exact pin locations.

Each I/O bank has its own VCCIO pins. A single device can support 1.5-V, 1.8-V, 2.5-V, and 3.3-V interfaces; each individual bank can support a different standard with different I/O voltages. Each bank also has dual-purpose VREF pins to support any one of the voltage-referenced standards (e.g., SSTL-3) independently. If an I/O bank does not use voltage-referenced standards, the $V_{\rm REF}$ pins are available as user I/O pins.

The Cyclone $V_{\rm CCINT}$ pins must always be connected to a 1.5-V power supply. If the $V_{\rm CCINT}$ level is 1.5 V, then input pins are 1.5-V, 1.8-V, 2.5-V, and 3.3-V tolerant. The $V_{\rm CCIO}$ pins can be connected to either a 1.5-V, 1.8-V, 2.5-V, or 3.3-V power supply, depending on the output requirements. The output levels are compatible with systems of the same voltage as the power supply (i.e., when $V_{\rm CCIO}$ pins are connected to a 1.5-V power supply, the output levels are compatible with 1.5-V systems). When $V_{\rm CCIO}$ pins are connected to a 3.3-V power supply, the output high is 3.3-V and is compatible with 3.3-V or 5.0-V systems. Table 2–14 summarizes Cyclone MultiVolt I/O support.

Table 2–14. Cyclone MultiVolt I/O Support Note (1)										
V (V)		Ir	nput Sign	al			Output Signal			
V _{CCIO} (V)	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V	1.5 V	1.8 V	2.5 V	3.3 V	5.0 V
1.5	✓	✓	√ (2)	√ (2)	_	✓	_	_	_	_
1.8	✓	✓	√ (2)	√ (2)	_	√ (3)	✓	_	_	_
2.5	_	_	✓	✓	_	√ (5)	√ (5)	✓	_	_
3.3	_	_	√ (4)	✓	√ (6)	√ (7)	√ (7)	√ (7)	✓	√ (8)

Notes to Table 2-14:

- (1) The PCI clamping diode must be disabled to drive an input with voltages higher than V_{CCIO}.
- (2) When V_{CCIO} = 1.5-V or 1.8-V and a 2.5-V or 3.3-V input signal feeds an input pin, higher pin leakage current is expected. Turn on Allow voltage overdrive for LVTTL / LVCMOS input pins in the Assignments > Device > Device and Pin Options > Pin Placement tab when a device has this I/O combinations.
- (3) When $V_{CCIO} = 1.8$ -V, a Cyclone device can drive a 1.5-V device with 1.8-V tolerant inputs.
- (4) When $V_{CCIO} = 3.3$ -V and a 2.5-V input signal feeds an input pin, the V_{CCIO} supply current will be slightly larger than expected.
- (5) When V_{CCIO} = 2.5-V, a Cyclone device can drive a 1.5-V or 1.8-V device with 2.5-V tolerant inputs.
- (6) Cyclone devices can be 5.0-V tolerant with the use of an external resistor and the internal PCI clamp diode.
- (7) When V_{CCIO} = 3.3-V, a Cyclone device can drive a 1.5-V, 1.8-V, or 2.5-V device with 3.3-V tolerant inputs.
- (8) When $V_{CCIO} = 3.3$ -V, a Cyclone device can drive a device with 5.0-V LVTTL inputs but not 5.0-V LVCMOS inputs.

Power Sequencing and Hot Socketing

Because Cyclone devices can be used in a mixed-voltage environment, they have been designed specifically to tolerate any possible power-up sequence. Therefore, the V_{CCIO} and V_{CCINT} power supplies may be powered in any order.

Signals can be driven into Cyclone devices before and during power up without damaging the device. In addition, Cyclone devices do not drive out during power up. Once operating conditions are reached and the device is configured, Cyclone devices operate as specified by the user.

Figure 3-1. Cyclone JTAG Waveforms TMS TDI TCK t _{JPXZ} t_{JPZX} t_{JPCO} TDO t_{JSH} t_{JSSU} Signal to Be Captured t_{JSCO} t_{JSXZ} t_{JSZX} -Signal to Be Driven

Figure 3–1 shows the timing requirements for the JTAG signals.

Table 3–4 shows the JTAG timing parameters and values for Cyclone devices.

Table 3-	-4. Cyclone JTAG Timing Parameters and Values	•		
Symbol	Parameter	Min	Max	Unit
t_{JCP}	TCK clock period	100	_	ns
t _{JCH}	TCK clock high time	50	_	ns
t _{JCL}	TCK clock low time	50	_	ns
t _{JPSU}	JTAG port setup time	20	_	ns
t _{JPH}	JTAG port hold time	45	_	ns
t _{JPCO}	JTAG port clock to output	_	25	ns
t_{JPZX}	JTAG port high impedance to valid output	_	25	ns
t_{JPXZ}	JTAG port valid output to high impedance	_	25	ns
t _{JSSU}	Capture register setup time	20	_	ns
t _{JSH}	Capture register hold time	45	_	ns
t_{JSCO}	Update register clock to output	_	35	ns
t _{JSZX}	Update register high impedance to valid output	_	35	ns
t _{JSXZ}	Update register valid output to high impedance	_	35	ns

Table 4–10.	Table 4–10. 3.3-V PCI Specifications (Part 2 of 2)										
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit					
V _{OH}	High-level output voltage	I _{OUT} = -500 μA	$0.9 \times V_{CCIO}$	_	_	V					
V _{OL}	Low-level output voltage	I _{OUT} = 1,500 μA	_	_	0.1 × V _{CCIO}	V					

Table 4–11	. SSTL-2 Class I Specificatio	ns				
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit
V _{CCIO}	Output supply voltage	_	2.375	2.5	2.625	V
V _{TT}	Termination voltage	_	V _{REF} - 0.04	V_{REF}	V _{REF} + 0.04	V
V _{REF}	Reference voltage	_	1.15	1.25	1.35	V
V _{IH}	High-level input voltage	_	V _{REF} + 0.18	_	3.0	V
V _{IL}	Low-level input voltage	_	-0.3	_	V _{REF} - 0.18	V
V _{OH}	High-level output voltage	I _{OH} = -8.1 mA (11)	V _{TT} + 0.57	_	_	V
V _{OL}	Low-level output voltage	I _{OL} = 8.1 mA (11)	_	_	V _{TT} – 0.57	V

Table 4–12. SSTL-2 Class II Specifications										
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit				
V _{CCIO}	Output supply voltage	_	2.3	2.5	2.7	V				
V _{TT}	Termination voltage	_	V _{REF} - 0.04	V _{REF}	V _{REF} + 0.04	V				
V_{REF}	Reference voltage	_	1.15	1.25	1.35	٧				
V _{IH}	High-level input voltage	_	V _{REF} + 0.18	_	V _{CCIO} + 0.3	V				
V _{IL}	Low-level input voltage	_	-0.3	_	V _{REF} - 0.18	٧				
V _{OH}	High-level output voltage	$I_{OH} = -16.4 \text{ mA}$ (11)	V _{TT} + 0.76	_	_	٧				
V _{OL}	Low-level output voltage	I _{OL} = 16.4 mA (11)	_	_	V _{TT} – 0.76	V				

Table 4-13	Table 4–13. SSTL-3 Class I Specifications (Part 1 of 2)								
Symbol	Parameter	Conditions	Minimum	Typical	Maximum	Unit			
V _{CCIO}	Output supply voltage	_	3.0	3.3	3.6	V			
V_{TT}	Termination voltage	_	V _{REF} - 0.05	V_{REF}	V _{REF} + 0.05	V			

Performance

The maximum internal logic array clock tree frequency is limited to the specifications shown in Table 4–19.

Table 4–19.	Table 4–19. Clock Tree Maximum Performance Specification										
Parameter	Definition	-6 Speed Grade		-7 Speed Grade			-8 Speed Grade			Units	
		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	UIIITS
Clock tree f _{MAX}	Maximum frequency that the clock tree can support for clocking registered logic		_	405	_	_	320		_	275	MHz

Table 4–20 shows the Cyclone device performance for some common designs. All performance values were obtained with the Quartus II software compilation of library of parameterized modules (LPM) functions or megafunctions. These performance values are based on EP1C6 devices in 144-pin TQFP packages.

Table 4-20	Table 4–20. Cyclone Device Performance										
	Design Size and Function	Mode	R	esources U	sed	F	Performanc	е			
Resource Used			LEs	M4K Memory Bits	M4K Memory Blocks	-6 Speed Grade (MHz)	-7 Speed Grade (MHz)	-8 Speed Grade (MHz)			
LE	16-to-1 multiplexer	_	21	_	_	405.00	320.00	275.00			
	32-to-1 multiplexer	_	44	_	_	317.36	284.98	260.15			
	16-bit counter	_	16	_	_	405.00	320.00	275.00			
	64-bit counter (1)	_	66	_	_	208.99	181.98	160.75			

Table 4–24. Ro	Table 4–24. Routing Delay Internal Timing Microparameter Descriptions							
Symbol Parameter								
t _{R4}	Delay for an R4 line with average loading; covers a distance of four LAB columns							
t _{C4}	Delay for an C4 line with average loading; covers a distance of four LAB rows							
t _{LOCAL}	Local interconnect delay							

Figure 4–1 shows the memory waveforms for the M4K timing parameters shown in Table 4–23.

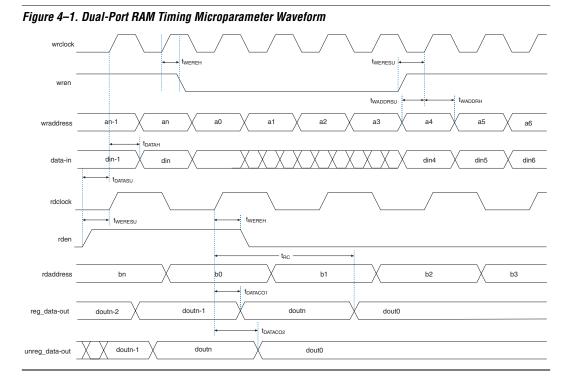


Table 4–29. C	yclone Global Clock External I/O Timing Parameters No	tes (1), (2) (Part 2 of 2)
Symbol	Parameter	Conditions
toutcople	Clock-to-output delay output or bidirectional pin using IOE output register with global clock enhanced PLL with default phase setting	C _{LOAD} = 10 pF

Notes to Table 4-29:

- (1) These timing parameters are sample-tested only.
- (2) These timing parameters are for IOE pins using a 3.3-V LVTTL, 24-mA setting. Designers should use the Quartus II software to verify the external timing for any pin.

Tables 4–30 through 4–31 show the external timing parameters on column and row pins for EP1C3 devices.

Table 4–30. EP1C3 Column Pin Global Clock External I/O Timing Parameters										
Cumbal	-6 Speed Grade -7 Speed Grade -8 Speed Grade									
Symbol	Min	Max	Min	Max	Min	Max	Unit			
t _{INSU}	3.085	_	3.547	_	4.009	_	ns			
t _{INH}	0.000	_	0.000	_	0.000	_	ns			
toutco	2.000	4.073	2.000	4.682	2.000	5.295	ns			
t _{INSUPLL}	1.795	_	2.063	_	2.332	_	ns			
t _{INHPLL}	0.000	_	0.000	_	0.000	_	ns			
toutcople	0.500	2.306	0.500	2.651	0.500	2.998	ns			

Table 4-31	Table 4–31. EP1C3 Row Pin Global Clock External I/O Timing Parameters										
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee	1124					
Symbol	Min	Max	Min	Max	Min	Max	Unit				
t _{INSU}	3.157	_	3.630	_	4.103	_	ns				
t _{INH}	0.000	_	0.000	_	0.000	_	ns				
t _{outco}	2.000	3.984	2.000	4.580	2.000	5.180	ns				
t _{INSUPLL}	1.867	_	2.146	_	2.426	_	ns				
t _{INHPLL}	0.000	_	0.000	_	0.000	_	ns				
toutcople	0.500	2.217	0.500	2.549	0.500	2.883	ns				

Tables 4-34 through 4-35 show the external timing parameters on column and row pins for EP1C6 devices.

Table 4-34	Table 4–34. EP1C6 Column Pin Global Clock External I/O Timing Parameters										
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee						
Symbol	Min	Max	Min	Max	Min	Max	Unit				
t _{INSU}	2.691	_	3.094	_	3.496	_	ns				
t _{INH}	0.000	_	0.000	_	0.000	_	ns				
toutco	2.000	3.917	2.000	4.503	2.000	5.093	ns				
t _{INSUPLL}	1.513	_	1.739	_	1.964	_	ns				
t _{INHPLL}	0.000	_	0.000	_	0.000	_	ns				
toutcople	0.500	2.038	0.500	2.343	0.500	2.651	ns				

Table 4–35. EP1C6 Row Pin Global Clock External I/O Timing Parameters										
Cumbal	-6 Spee	d Grade	-7 Spee	d Grade	-8 Spee					
Symbol	Min	Max	Min	Max	Min	Max	Unit			
t _{INSU}	2.774	_	3.190	_	3.605	_	ns			
t _{INH}	0.000	_	0.000	_	0.000	_	ns			
toutco	2.000	3.817	2.000	4.388	2.000	4.963	ns			
t _{INSUPLL}	1.596	_	1.835	_	2.073	_	ns			
t _{INHPLL}	0.000	_	0.000	_	0.000	_	ns			
toutcople	0.500	1.938	0.500	2.228	0.500	2.521	ns			

Tables 4–36 through 4–37 show the external timing parameters on column and row pins for EP1C12 devices.

	Table 4–36. EP1C12 Column Pin Global Clock External I/O Timing Parameters (Part 1 of 2)											
Cumbal	-6 Speed Grade -7 Speed Grade -8 Speed Grade											
Symbol	Min	in Max Min Max Min Max										
t _{INSU}	2.510	_	2.885	_	3.259	_	ns					
t _{INH}	0.000	_	0.000	_	0.000	_	ns					
tO _{UTCO}	2.000	3.798	2.000	4.367	2.000	4.940	ns					
t _{INSUPLL}	1.588	_	1.824	_	2.061	_	ns					

Table 4-44. 0	Sycione I/O S	tandard Out	put Delay A	dders for Sla	ow Slew Rat	e on Columi	n Pins (Part	2 of 2)
I/O Stor	1/0.01		-6 Speed Grade		d Grade	-8 Spee		
I/O Star	iuaru	Min	Max	Min	Max	Min	Max	Unit
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps
	4 mA	_	5,109	_	5,875	_	6,641	ps
	8 mA	_	4,793	_	5,511	_	6,230	ps
SSTL-3 class I		_	1,390	_	1,598	_	1,807	ps
SSTL-3 class I	I	_	989	_	1,137	_	1,285	ps
SSTL-2 class I		_	1,965	_	2,259	_	2,554	ps
SSTL-2 class I	I	_	1,692	_	1,945		2,199	ps
LVDS	·	_	802	_	922	_	1,042	ps

		-6 Sno	ad Grado	-7 Sno	ed Grade	-8 Sno	ed Grade	
I/O Sta	ndard	-6 Speed Grade		-/ Spec	tu ulaut	-o she	Unit	
·		Min	Max	Min	Max	Min	Max	
LVCMOS	2 mA	_	1,800	_	2,070	_	2,340	ps
	4 mA	_	1,311	_	1,507	_	1,704	ps
	8 mA	_	945	_	1,086	_	1,228	ps
	12 mA	_	807	_	928	_	1,049	ps
3.3-V LVTTL	4 mA	_	1,831	_	2,105	_	2,380	ps
	8 mA	_	1,484	_	1,705	_	1,928	ps
	12 mA	_	973	_	1,118	_	1,264	ps
	16 mA	_	1,012	_	1,163	_	1,315	ps
	24 mA	_	838	_	963	_	1,089	ps
2.5-V LVTTL	2 mA	_	2,747	_	3,158	_	3,570	ps
	8 mA	_	1,757	_	2,019	_	2,283	ps
	12 mA	_	1,763	_	2,026	_	2,291	ps
	16 mA	_	1,623	_	1,865	_	2,109	ps
1.8-V LVTTL	2 mA	_	5,506	_	6,331	_	7,157	ps
	8 mA	_	4,220	_	4,852	_	5,485	ps
	12 mA	_	4,008	_	4,608	_	5,209	ps
1.5-V LVTTL	2 mA	_	6,789	_	7,807	_	8,825	ps
	4 mA	_	5,109	_	5,875	_	6,641	ps
	8 mA	_	4,793	_	5,511	_	6,230	ps
3.3-V PCI		_	923	_	1,061	_	1,199	ps

Table 4–45. Cyclone I/O	Table 4–45. Cyclone I/O Standard Output Delay Adders for Slow Slew Rate on Row Pins (Part 2 of 2)										
L/O Otandard	-6 Speed Grade		-7 Speed Grade		-8 Speed Grade						
I/O Standard	Min	Max	Min	Max	Min	Max	Unit				
SSTL-3 class I	_	1,390	_	1,598	_	1,807	ps				
SSTL-3 class II	_	989	_	1,137	_	1,285	ps				
SSTL-2 class I	_	1,965	_	2,259	_	2,554	ps				
SSTL-2 class II	_	1,692	_	1,945	_	2,199	ps				
LVDS	_	802	_	922	_	1,042	ps				

Note to Tables 4–40 through 4–45:

Tables 4–46 through 4–47 show the adder delays for the IOE programmable delays. These delays are controlled with the Quartus II software options listed in the Parameter column.

Parameter	Setting	-6 Spee	-6 Speed Grade		-7 Speed Grade		d Grade	Unit
		Min	Max	Min	Max	Min	Max	UIII
Decrease input delay to	Off	_	155	_	178	_	201	ps
internal cells	Small	_	2,122	_	2,543	_	2,875	ps
	Medium	_	2,639	_	3,034	_	3,430	ps
	Large	_	3,057	_	3,515	_	3,974	ps
	On	_	155	_	178	_	201	ps
Decrease input delay to	Off	_	0	_	0	_	0	ps
input register	On	_	3,057	_	3,515	_	3,974	ps
Increase delay to output	Off	_	0	_	0	_	0	ps
pin	On	_	552	_	634	_	717	ps

⁽¹⁾ EP1C3 devices do not support the PCI I/O standard.



5. Reference and Ordering Information

C51005-1.4

Software

Cyclone® devices are supported by the Altera® Quartus® II design software, which provides a comprehensive environment for system-on-a-programmable-chip (SOPC) design. The Quartus II software includes HDL and schematic design entry, compilation and logic synthesis, full simulation and advanced timing analysis, SignalTap® II logic analysis, and device configuration.



For more information about the Quartus II software features, refer to the *Quartus II Handbook*.

The Quartus II software supports the Windows 2000/NT/98, Sun Solaris, Linux Red Hat v7.1 and HP-UX operating systems. It also supports seamless integration with industry-leading EDA tools through the NativeLink® interface.

Device Pin-Outs

Device pin-outs for Cyclone devices are available on the Altera website (www.altera.com) and in the *Cyclone Device Handbook*.

Ordering Information

Figure 5–1 describes the ordering codes for Cyclone devices. For more information about a specific package, refer to the *Package Information for Cyclone Devices* chapter in the *Cyclone Device Handbook*.